skinner innovations

HST Series Heat Detector Tester

For Rate Compensated Fire Detectors and Thermal Switches

HST Series

***Safe** Test tool for rate compensated thermal fire detectors and thermal switches*

The HST series tester was developed in response to the need for a safe and non-destructive means of testing rate compensated fire detectors and thermal switches. The tool consists of a special heater and control unit, specifically designed to be placed on top of a long reaching pole which is then raised up to the detector to be tested.

PRODUCT FEATURES

- Built with safety in mind- The HST series tester maintains a much safer working temperature than heat guns, soldering irons, or other commonly used testing means (compare common testing methods at www.skinnerinnovations.com/files/testmethodcomparison.pdf)
- Non-destructive- The HST tester applies only the required amount of heat at an acceptable rate and eliminates sensor set-point shift from overheating during testing
- The only portable rate compensated detector tester
- Cordless technology- uses 2.7 Amp-hour long life batteries
- Compatibility with the industry's most common long reaching poles (sold separately). The unique test head design makes it possible to easily place the tester onto sensors 30 feet overhead.
- **The temperature control unit maintains a safe, non destructive temperature by applying a measured amount of heat and provides visual indication of the temperature/test progress.**
- Large, easy to see, LED indicator light
- Remote Temperature output option- for direct temp reading

The HST's long battery life, high temperature range, and rugged design have been proven in the industry's most extreme environments. The HST series tester is used on offshore oil rigs, refineries, ships, engine and turbine enclosures, and any other area where rate compensated fire detectors or thermal switches are used.

No other portable thermal detector tester is capable of measuring test temperature and monitoring test progress. The calibrated HST test tool will provide information on device failures that other commonly used testing means are incapable of providing.